PHU101NQ03LT

N-channel TrenchMOS logic level FET

Rev. 04 — 30 June 2009

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Simple gate drive required due to low gate charge
- Suitable for logic level gate drive sources

1.3 Applications

■ DC-to-DC convertors

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	30	V
I _D	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V};$ see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	75	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	166	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 5 \text{ V}; I_D = 50 \text{ A};$ $V_{DS} = 15 \text{ V}; T_j = 25 \text{ °C};$ see Figure 11	-	8	-	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 9}}{\text{10}};$ $S_j = \frac{\text{Figure 10}}{\text{10}}$	-	4.5	5.5	mΩ



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol	
1	G	gate		_	
2	D	drain	mb	D	
3	S	source		$G \longrightarrow \overline{A}$	
mb	D	mounting base; connected to drain	1 2 3	mbb076 S	
			SOT533 (IPAK)		

3. Ordering information

Table 3. Ordering information

Type number	Package				
	Name	Description	Version		
PHU101NQ03LT	IPAK	plastic single-ended package (IPAK); 3 leads (in-line)	SOT533		

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	30	V
V_{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	30	V
V_{GS}	gate-source voltage		-20	20	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 1</u>	-	75	Α
		V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	75	Α
I _{DM}	peak drain current	$t_p \le 10 \mu\text{s}; \text{ pulsed}; T_{mb} = 25 ^{\circ}\text{C}; \text{ see } \underline{\text{Figure 3}}$	-	240	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	166	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
V_{GSM}	peak gate-source voltage	pulsed; $δ = 25$ %; $T_j ≤ 150$ °C; $t_p ≤ 50$ μs	-25	25	V
Source-dra	ain diode				
Is	source current	$T_{mb} = 25 ^{\circ}C$	-	75	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	240	Α
Avalanche	ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 43 A; V_{sup} ≤ 15 V; unclamped; t_p = 0.19 ms; R_{GS} = 50 Ω	-	185	mJ

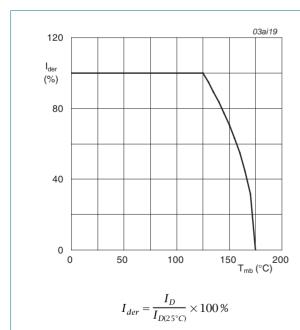
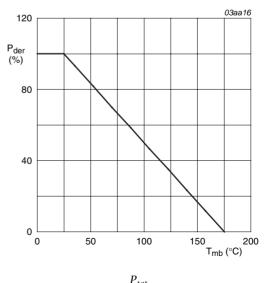
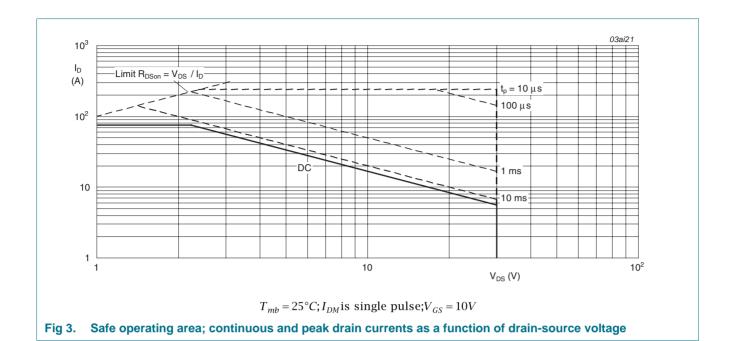


Fig 1. Normalized continuous drain current as a function of mounting base temperature



 $P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$

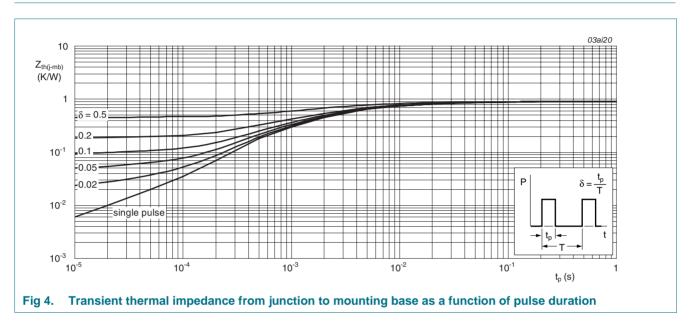
Fig 2. Normalized total power dissipation as a function of mounting base temperature



5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j\text{-}mb)}$	thermal resistance from junction to mounting base	see <u>Figure 4</u>	-	-	0.19	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	vertical in free air	-	70	-	K/W



6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	27	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see <u>Figure 7</u> ; see <u>Figure 8</u>	-	-	2.9	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 175 °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	0.6	-	-	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	1	1.9	2.5	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	1	μA
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nA
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nA
R _{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	4.5	5.5	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 175 °C;$ see <u>Figure 9</u> ; see <u>Figure 10</u>	-	10.5	13.5	mΩ
		$V_{GS} = 5 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 25 \text{ °C}$; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	5.8	7.5	mΩ
Dynamic (characteristics					
Q _{G(tot)}	total gate charge	$I_D = 50 \text{ A}; V_{DS} = 15 \text{ V}; V_{GS} = 5 \text{ V};$	-	23	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 11</u>	-	10.5	-	nC
Q_{GD}	gate-drain charge		-	8	-	nC
C _{iss}	input capacitance	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	2180	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 12</u>	-	600	-	pF
C _{rss}	reverse transfer capacitance		-	225	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = 15 V; R_L = 0.6 Ω ; V_{GS} = 4.5 V;	-	23	-	ns
t _r	rise time	$R_{G(ext)} = 5.6 \Omega; T_j = 25 \text{ °C}; I_D = 25 \text{ A}$	-	90	-	ns
t _{d(off)}	turn-off delay time		-	37	-	ns
t _f	fall time		-	33	-	ns
Source-di	rain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see <u>Figure 13</u>	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 10 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	37	-	ns
Q _r	recovered charge	$V_{DS} = 25 \text{ V; } T_j = 25 \text{ °C}$	-	33	-	nC
	<u> </u>		-			

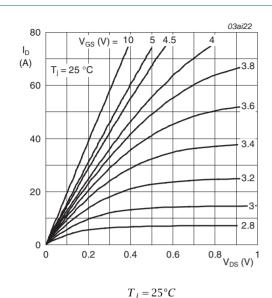
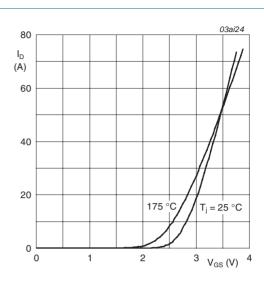
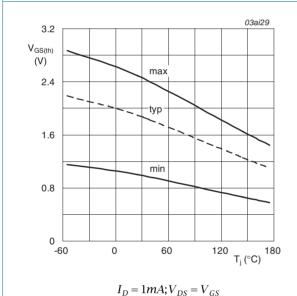


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



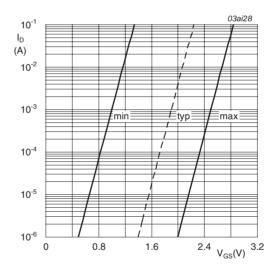
 $T_j = 25$ °C and 175°C; $V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values



ig 7. Gate-source threshold voltage as a function of

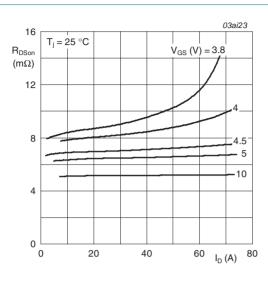
junction temperature



 $T_j=25$ °C; $V_{DS}=5V$

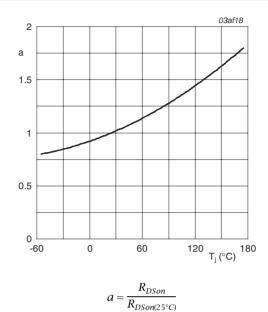
Fig 8. Sub-threshold drain current as a function of gate-source voltage

7 of 13



 $T_i = 25^{\circ}C$

Drain-source on-state resistance as a function of drain current; typical values



 $R_{DSon(25^{\circ}C)}$ red drain-source on-state resis

Fig 10. Normalized drain-source on-state resistance factor as a function of junction temperature

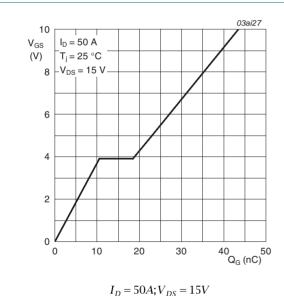
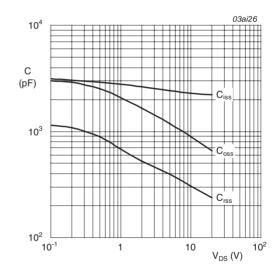


Fig 11. Gate-source voltage as a function of gate

charge; typical values



 $V_{GS} = 0V; f = 1MHz$

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

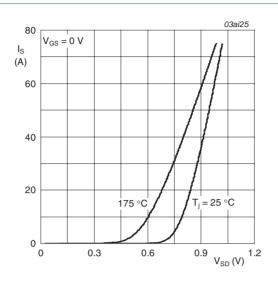
Fig 9.

8 of 13

Product data sheet

9 of 13

N-channel TrenchMOS logic level FET



 $T_j = 25^{\circ} C \text{ and } 175^{\circ} C; V_{GS} = 0V$

Fig 13. Source current as a function of source-drain voltage; typical values

7. Package outline

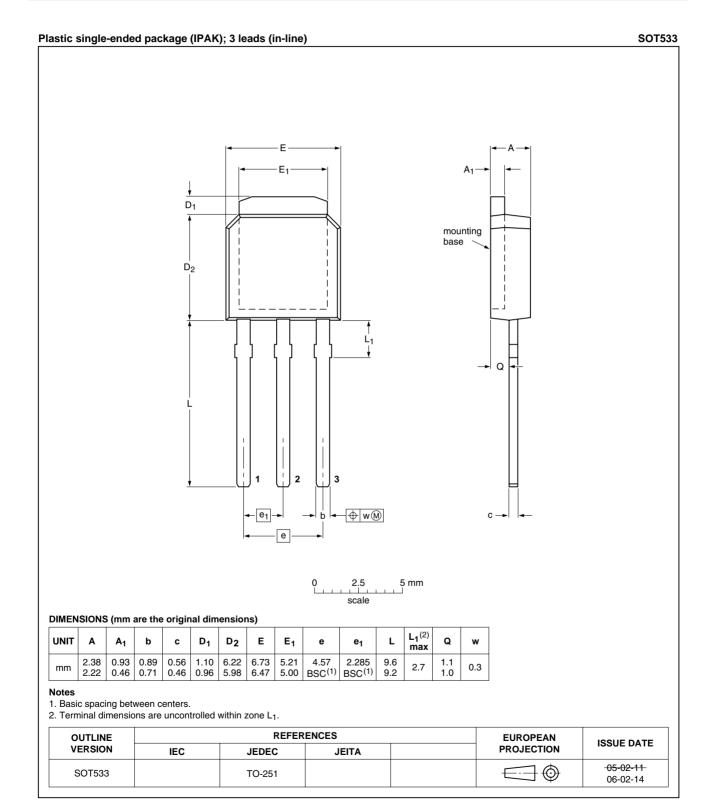


Fig 14. Package outline SOT533 (IPAK)

11 of 13

N-channel TrenchMOS logic level FET

Revision history

Table 7. **Revision history**

Product data sheet

Document ID	Release date	Data sheet status	Change notice	Supersedes
PHU101NQ03LT_4	20090630	Product data sheet	-	PHP_PHU101NQ03LT_3
Modifications:	 The format of this guidelines of NXP 	data sheet has been re Semiconductors.	edesigned to comply	with the new identity
	 Legal texts have b 	een adapted to the ne	w company name wh	nere appropriate.
	 Type number PHL 	J101NQ03LT separate	d from data sheet PH	HP_PHU101NQ03LT_3.
PHP_PHU101NQ03LT_3	20051117	Product data sheet	CPC # 200309016	PHP_PHU101NQ03LT-02
PHP_PHU101NQ03LT-02 (9397 750 10927)	20030225	Product data	-	PHP_PHD_PHB_PHU101 NQ03LT-01
PHP_PHD_PHB_PHU101 NQ03LT-01 (9397 750 09307)	20020220	Product data	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

9.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

9.3 Disclaimers

General — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Quick reference data — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Export control — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from national authorities.

9.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

TrenchMOS — is a trademark of NXP B.V.

10. Contact information

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: salesaddresses@nxp.com

PHU101NQ03LT

N-channel TrenchMOS logic level FET

11. Contents

1	Product profile	1
1.1	General description	1
1.2	Features and benefits	1
1.3	Applications	1
1.4	Quick reference data	1
2	Pinning information	2
3	Ordering information	2
4	Limiting values	3
5	Thermal characteristics	5
6	Characteristics	6
7	Package outline	10
8	Revision history	11
9	Legal information	12
9.1	Data sheet status	12
9.2	Definitions	12
9.3	Disclaimers	12
9.4	Trademarks	12
10	Contact information	12

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.



